

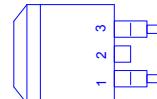
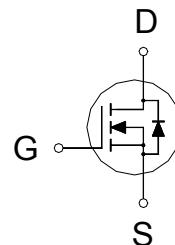
NIKO-SEM
**N-Channel Enhancement Mode
Field Effect Transistor**
P2610ASG

TO-263

Halogen-Free & Lead-Free

**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
100	26mΩ	40A



1. GATE
2. DRAIN
3. SOURCE

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Gate-Source Voltage		V_{GS}	± 20	V
Continuous Drain Current ¹	$T_C = 25^\circ\text{C}$	I_D	40	A
	$T_C = 100^\circ\text{C}$		31	
Pulsed Drain Current ²		I_{DM}	120	
Avalanche Current		I_{AS}	54	
Avalanche Energy	$L = 0.1\text{mH}$	E_{AS}	145	mJ
Power Dissipation	$T_C = 25^\circ\text{C}$	P_D	89	W
	$T_C = 100^\circ\text{C}$		57	
Operating Junction & Storage Temperature Range		T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATING

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		1.4	°C / W
Junction-to-Ambient	$R_{\theta JA}$		50	

¹limited by maximum junction temperature.²limited by package.**ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	100			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1.5	2.3	4	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0\text{V}, V_{GS} = \pm 20\text{V}$			± 250	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 80\text{V}, V_{GS} = 0\text{V}$			1	μA
		$V_{DS} = 80\text{V}, V_{GS} = 0\text{V}, T_J = 125^\circ\text{C}$			10	
On-State Drain Current ¹	$I_{D(\text{ON})}$	$V_{DS} = 10\text{V}, V_{GS} = 10\text{V}$	120			A
Drain-Source On-State Resistance ¹	$R_{DS(\text{ON})}$	$V_{GS} = 10\text{V}, I_D = 27.5\text{A}$		22	26	$\text{m}\Omega$
Forward Transconductance ¹	g_{fs}	$V_{DS} = 10\text{V}, I_D = 27.5\text{A}$		53		S

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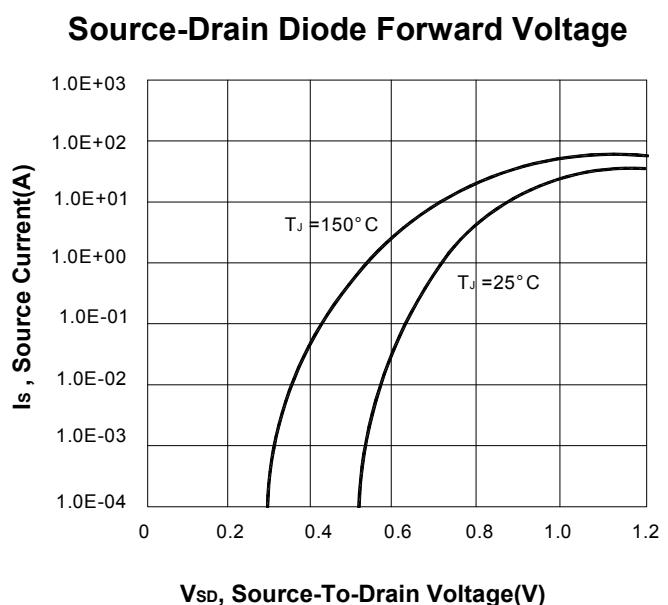
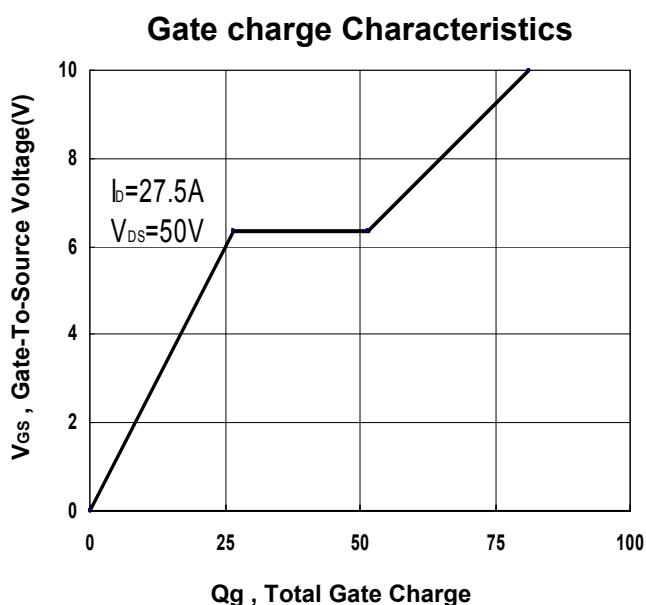
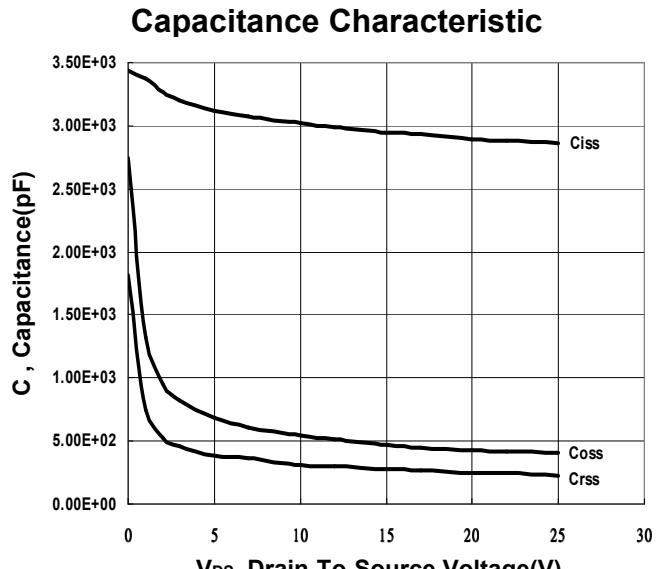
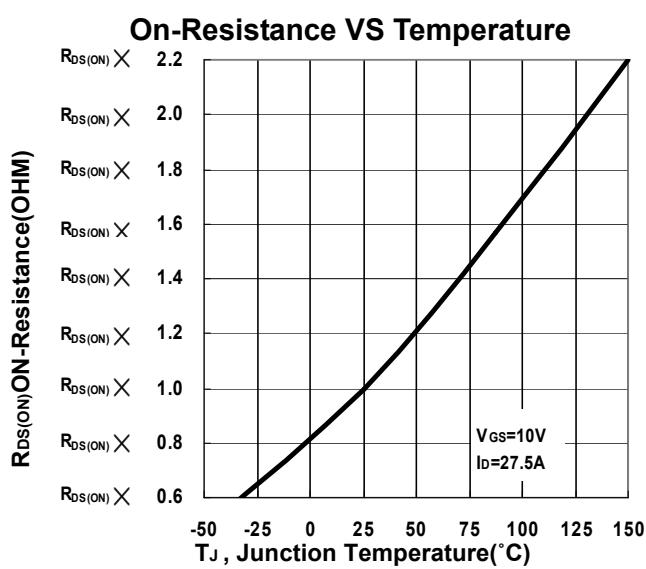
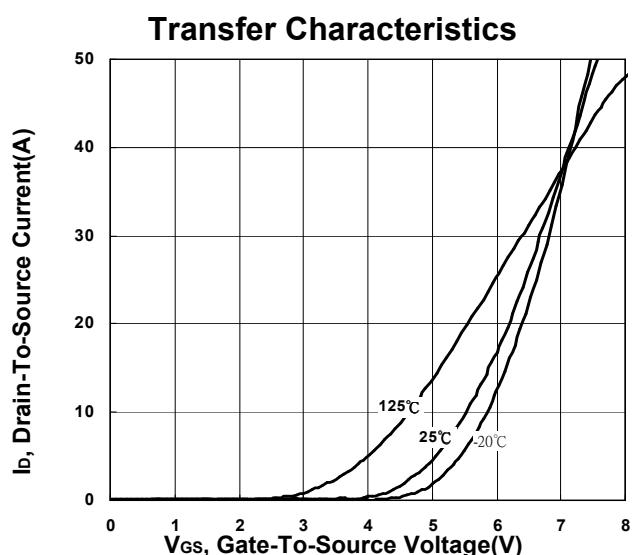
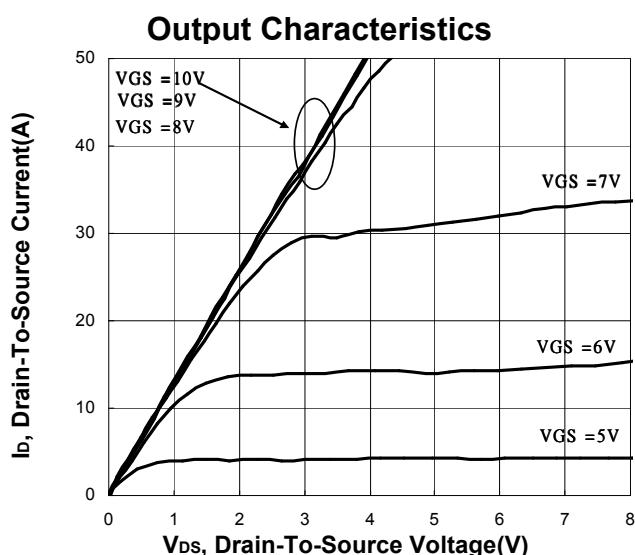
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DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$		5020		pF
Output Capacitance	C_{oss}			311		
Reverse Transfer Capacitance	C_{rss}			198		
Total Gate Charge ²	Q_g	$V_{DS} = 50V, V_{GS} = 10V,$ $I_D = 27.5A$		82.9		nC
Gate-Source Charge ²	Q_{gs}			26.9		
Gate-Drain Charge ²	Q_{gd}			26.3		
Turn-On Delay Time ²	$t_{d(on)}$	$V_{DD} = 50V,$ $I_D \geq 27.5A, V_{GS} = 10V, R_{GEN} = 6\Omega$		38		nS
Rise Time ²	t_r			70		
Turn-Off Delay Time ²	$t_{d(off)}$			94		
Fall Time ²	t_f			38		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ C$)						
Continuous Current	I_S			50	A	
Forward Voltage ¹	V_{SD}	$I_F = 27.5A, V_{GS} = 0V$		1.1	V	
Reverse Recovery Time	t_{rr}	$I_F = 27.5A, dI_F/dt = 100A / \mu S$		120		nS
Reverse Recovery Charge	Q_{rr}			465		nC

¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.

REMARK: THE PRODUCT MARKED WITH "P2610ASG", DATE CODE or LOT #

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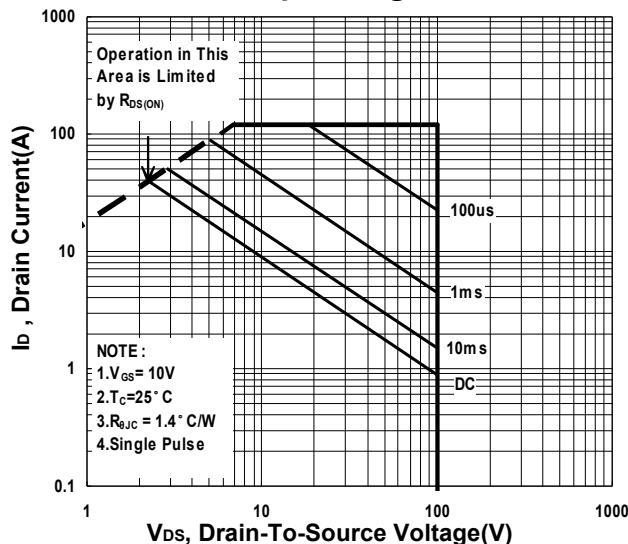
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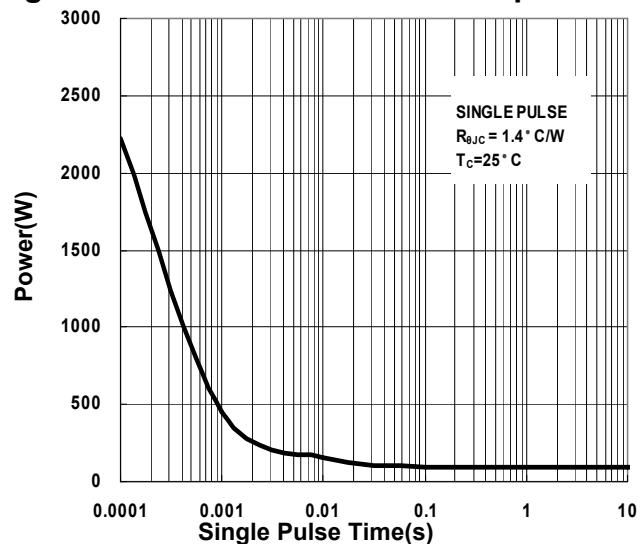
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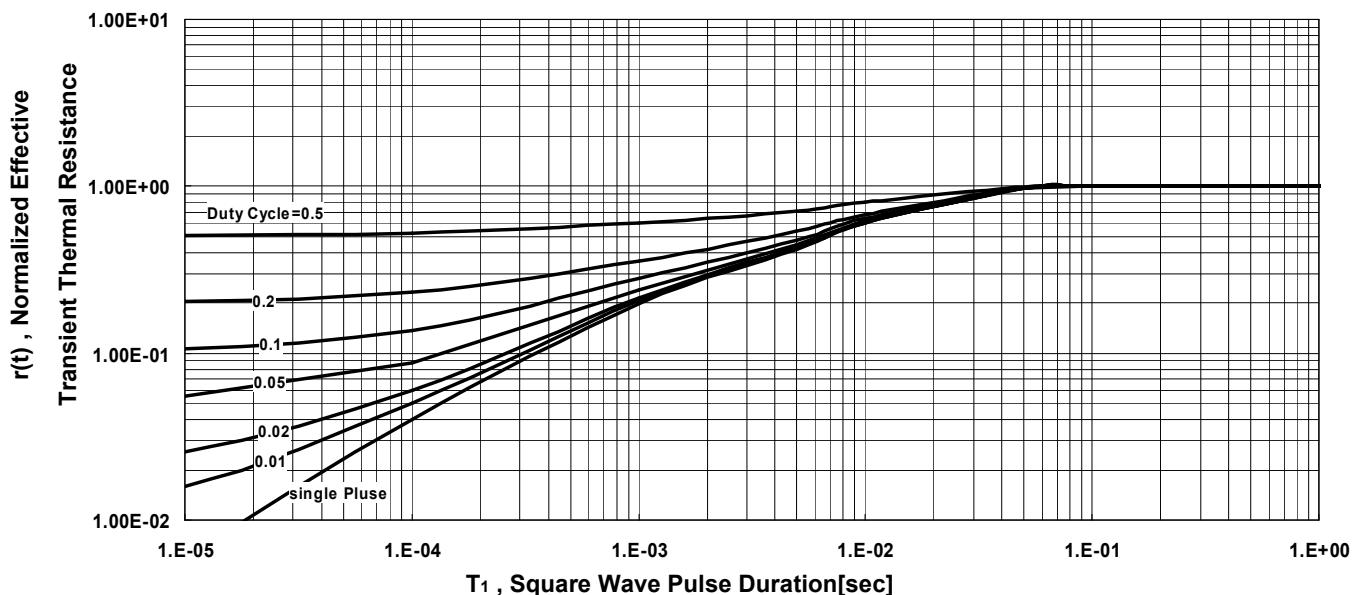
Safe Operating Area



Single Pulse Maximum Power Dissipation



Transient Thermal Response Curve



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TO-263 (D²PAK) MECHANICAL DATA

Dimension	mm			Dimension	mm		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A	14.6	15.1	15.8	H	1.17	1.27	1.4
B	4.4	4.57	4.8	I	9.8	10.16	10.4
C	1.22		1.45	J			
D	2.59	2.69	2.79	K		1.5	1.75
E	0.36		0.5	L	0.76		1.00
F	0	0.1	0.3	M		5.08	
G	8.6	9.15	9.25	N			

